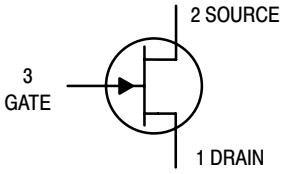
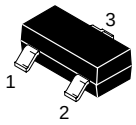
JFET Amplifiers
N–Channel

BFR30LT1
BFR31LT1





CASE 318–08, STYLE 10
SOT–23 (TO–236AB)

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain–Source Voltage	V_{DS}	25	Vdc
Gate–Source Voltage	V_{GS}	25	Vdc

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Dissipation(1) T_A = 25°C Derate above 25°C	P_D	225 1.8	mW mW/°C
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	556	°C/W
Total Device Dissipation Alumina Substrate,(2) T_A = 25°C Derate above 25°C	P_D	300 2.4	mW mW/°C
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	417	°C/W
Junction and Storage Temperature	T_J, T_{stg}	–55 to +150	°C

DEVICE MARKING

BFR30LT1 = M1; BFR31LT1 = M2

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic			Symbol	Min	Max	Unit
OFF CHARACTERISTICS						
Gate Reverse Current	(V_{GS} = 10 Vdc, V_{DS} = 0)		I_{GSS}	—	0.2	nAdc
Gate Source Cutoff Voltage	(I_D = 0.5 nAdc, V_{DS} = 10 Vdc)	BFR30 BFR31	$V_{GS(OFF)}$	— —	5.0 2.5	Vdc
Gate Source Voltage	(I_D = 1.0 mAdc, V_{DS} = 10 Vdc) (I_D = 50 μAdc, V_{DS} = 10 Vdc)	BFR30 BFR31 BFR30 BFR31	V_{GS}	–0.7 — — —	–3.0 –1.3 –4.0 –2.0	Vdc

1. Device mounted on FR4 glass epoxy printed circuit board using the recommended footprint.
2. Alumina = 0.4 x 0.3 x 0.024 in. 99.5% alumina.

November, 2001 – Rev. 2
Publication Order Number:
BFR30LT1/D

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted) (Continued)

Characteristic			Symbol	Min	Max	Unit
ON CHARACTERISTICS						
Zero–Gate–Voltage Drain Current	(V_{DS} = 10 Vdc, V_{GS} = 0)	BFR30	I_{DSS}	4.0	10	mAdc
		BFR31		1.0	5.0	
SMALL–SIGNAL CHARACTERISTICS						
Forward Transconductance			$\|y_{fs}\|$			mAdc
(I_D = 1.0 mAdc, V_{DS} = 10 Vdc, f = 1.0 kHz)		BFR30		1.0	4.0	
		BFR31		1.5	4.5	
(I_D = 200 μAdc, V_{DS} = 10 Vdc, f = 1.0 kHz)		BFR30		0.5	—	
		BFR31		0.75	—	
Output Admittance			$\|y_{os}\|$			μAdc
(I_D = 1.0 mAdc, V_{DS} = 10 Vdc, f = 1.0 kHz)		BFR30		40	25	
(I_D = 200 μAdc, V_{DS} = 10 Vdc)		BFR31		20	15	
Input Capacitance	(I_D = 1.0 mAdc, V_{DS} = 10 Vdc, f = 1.0 MHz)		C_{iss}	—	5.0	pF
	(I_D = 200 μAdc, V_{DS} = 10 Vdc, f = 1.0 MHz)			—	4.0	
Reverse Transfer Capacitance	(I_D = 1.0 mAdc, V_{DS} = 10 Vdc, f = 1.0 MHz)		C_{rss}	—	1.5	pF
	(I_D = 200 μAdc, V_{DS} = 10 Vdc, f = 1.0 MHz)			—	1.5	

TYPICAL CHARACTERISTICS

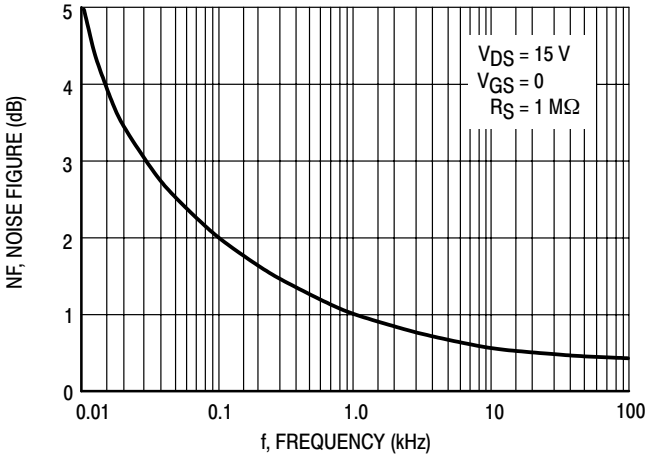


Figure 1. Noise Figure versus Frequency

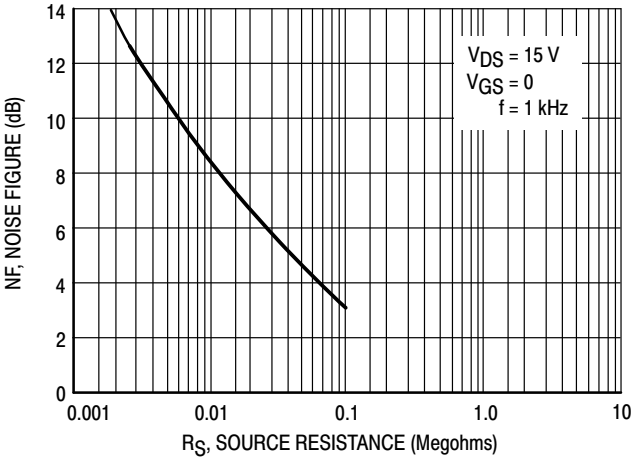


Figure 2. Noise Figure versus Source Resistance

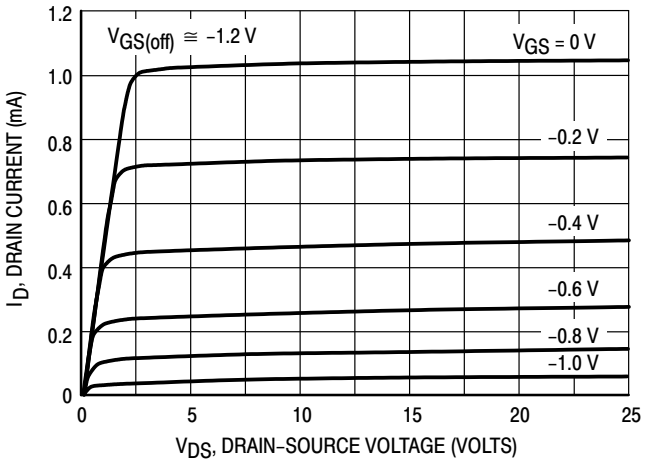


Figure 3. Typical Drain Characteristics

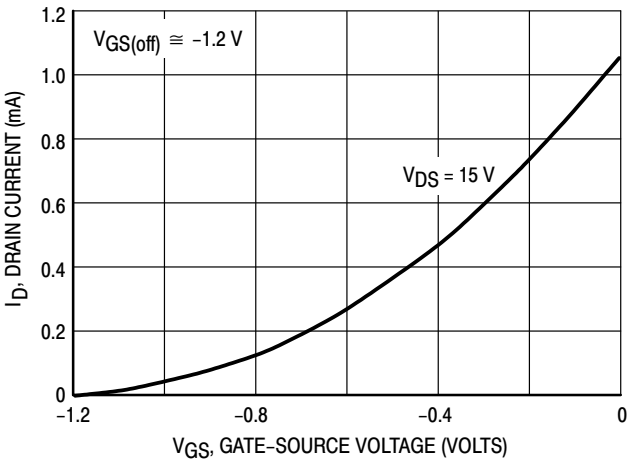


Figure 4. Common Source Transfer Characteristics

TYPICAL CHARACTERISTICS

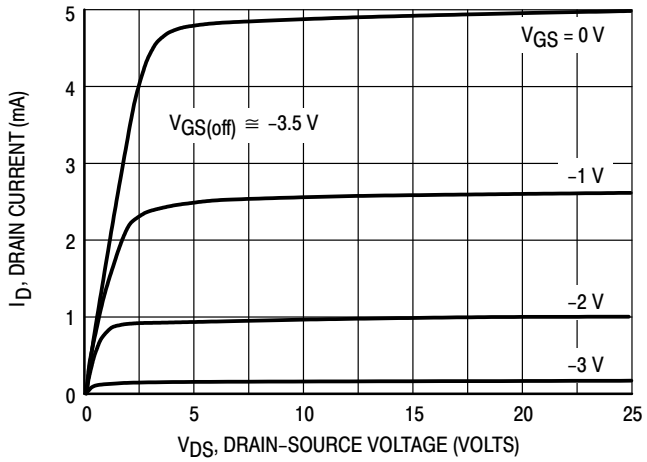


Figure 5. Typical Drain Characteristics

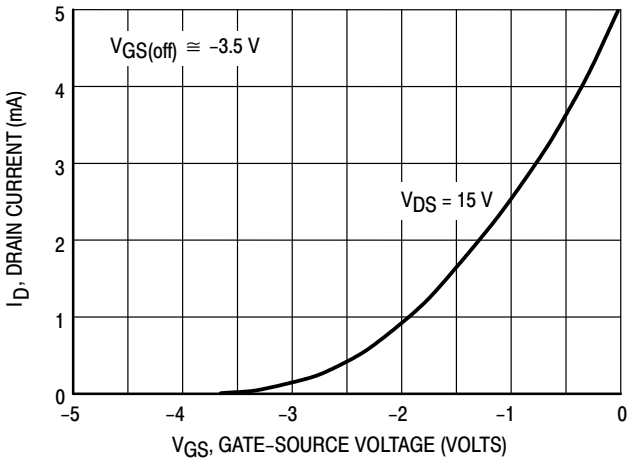


Figure 6. Common Source Transfer Characteristics

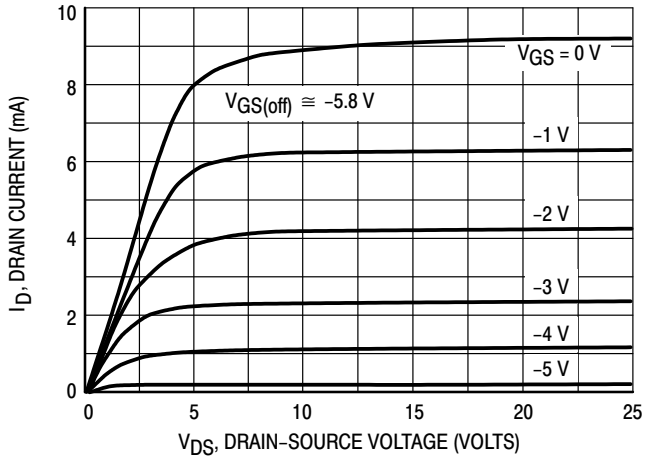


Figure 7. Typical Drain Characteristics

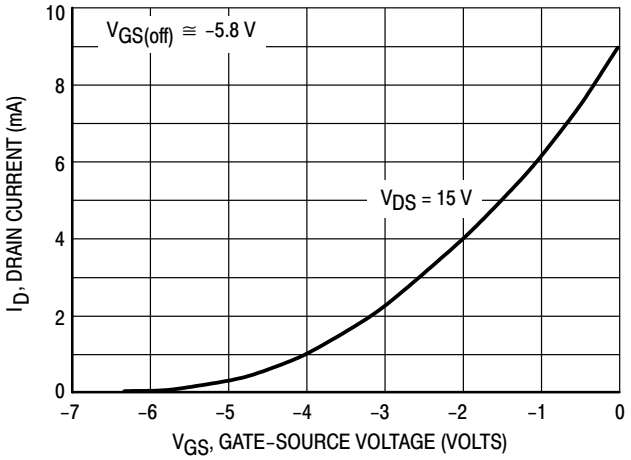


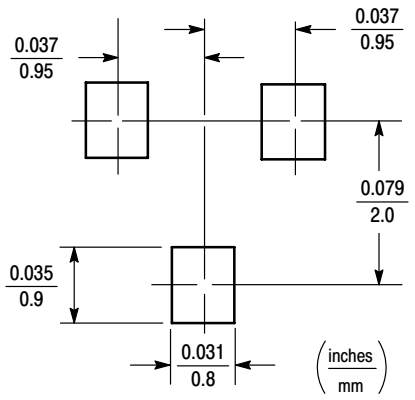
Figure 8. Common Source Transfer Characteristics

Note: Graphical data is presented for dc conditions. Tabular data is given for pulsed conditions (Pulse Width = 630 ms, Duty Cycle = 10%). Under dc conditions, self heating in higher I_{DSS} units reduces I_{DSS}.

INFORMATION FOR USING THE SOT–23 SURFACE MOUNT PACKAGE

MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



SOT–23

SOT–23 POWER DISSIPATION

The power dissipation of the SOT–23 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by $T_{J(max)}$, the maximum rated junction temperature of the die, $R_{\theta JA}$, the thermal resistance from the device junction to ambient, and the operating temperature, T_A. Using the values provided on the data sheet for the SOT–23 package, P_D can be calculated as follows:

$$P_D = \frac{T_{J(max)} - T_A}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature T_A of 25°C, one can calculate the power dissipation of the device which in this case is 225 milliwatts.

$$P_D = \frac{150°C - 25°C}{556°C/W} = 225 \text{ milliwatts}$$

The 556°C/W for the SOT–23 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 225 milliwatts. There are other alternatives to achieving higher power dissipation from the SOT–23 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad™. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

SOLDERING PRECAUTIONS

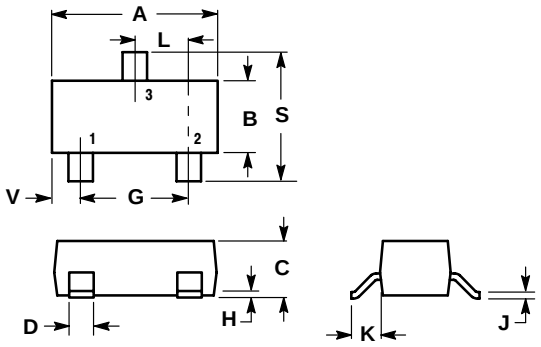
The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

PACKAGE DIMENSIONS

SOT−23 (TO−236AB)
CASE 318−08
ISSUE AF



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.1102	0.1197	2.80	3.04
B	0.0472	0.0551	1.20	1.40
C	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
H	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
K	0.0140	0.0285	0.35	0.69
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.1039	2.10	2.64
V	0.0177	0.0236	0.45	0.60

STYLE 10:
PIN 1. DRAIN
2. SOURCE
3. GATE

Notes

Thermal Clad is a trademark of the Bergquist Company.

PUBLICATION ORDERING INFORMATION

Literature Fulfillment:
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